



Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from,Europe,America and south Asia,supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of “Quality Parts,Customers Priority,Honest Operation,and Considerate Service”,our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip,ALPS,ROHM,Xilinx,Pulse,ON,Everlight and Freescale. Main products comprise IC,Modules,Potentiometer,IC Socket,Relay,Connector.Our parts cover such applications as commercial,industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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OptiMOS[®]-P Small-Signal-Transistor Feature

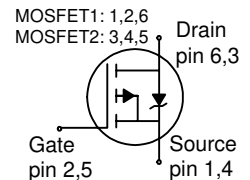
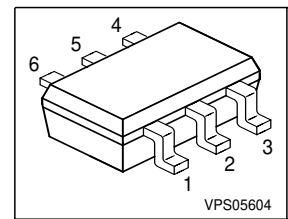
- Dual P-Channel
- Enhancement mode
- Super Logic Level (2.5 V rated)
- 150°C operating temperature
- Avalanche rated
- dv/dt rated
- Pb-free lead plating; RoHS compliant
- Qualified according to AEC Q101
- Halogen-free according to IEC61249-2-21



Product Summary

V_{DS}	-20	V
$R_{DS(on)}$	1.2	Ω
I_D	-0.39	A

PG-SOT-363



Type	Package	Tape & Reel	Marking
BSD 223P	PG-SOT-363	H6327: 3000pcs/r	X1s

Maximum Ratings, at $T_j = 25\text{ }^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Value	Unit
Continuous drain current	I_D		A
$T_A=25\text{ }^\circ\text{C}$		-0.39	
$T_A=70\text{ }^\circ\text{C}$		-0.31	
Pulsed drain current	$I_D \text{ puls}$	-1.56	
$T_A=25\text{ }^\circ\text{C}$			
Avalanche energy, single pulse	E_{AS}	1.4	mJ
$I_D=-0.39\text{ A}$, $V_{DD}=-10\text{ V}$, $R_{GS}=25\Omega$			
Reverse diode dv/dt	dv/dt	-6	kV/ μs
$I_S=-0.39\text{ A}$, $V_{DS}=-16\text{ V}$, $di/dt=200\text{ A}/\mu\text{s}$, $T_{jmax}=150\text{ }^\circ\text{C}$			
Gate source voltage	V_{GS}	± 12	V
Power dissipation	P_{tot}	0.25	W
$T_A=25\text{ }^\circ\text{C}$			
Operating and storage temperature	T_j, T_{stg}	-55... +150	$^\circ\text{C}$
IEC climatic category; DIN IEC 68-1		55/150/56	
ESD Class		Class 0	
JESD22-A114-HBM			

Thermal Characteristics

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Characteristics					
Thermal resistance, junction - soldering point	R_{thJS}	-	-	180	K/W
Thermal resistance, junction - ambient, leaded	R_{thJA}	-	-	500	

Electrical Characteristics, at $T_j = 25\text{ }^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Static Characteristics					
Drain-source breakdown voltage $V_{GS}=0, I_D=-250\mu\text{A}$	$V_{(BR)DSS}$	-20	-	-	V
Gate threshold voltage, $V_{GS} = V_{DS}$ $I_D=-1.5\mu\text{A}$	$V_{GS(th)}$	-0.6	-0.9	-1.2	
Zero gate voltage drain current $V_{DS}=-20\text{V}, V_{GS}=0, T_j=25^\circ\text{C}$ $V_{DS}=-20\text{V}, V_{GS}=0, T_j=150^\circ\text{C}$	I_{DSS}	-	-0.1 -10	-1 -100	μA
Gate-source leakage current $V_{GS}=-12\text{V}, V_{DS}=0$	I_{GSS}	-	-10	-100	
Drain-source on-state resistance $V_{GS}=-2.5\text{V}, I_D=-0.29\text{A}$	$R_{DS(on)}$	-	1.27	2.1	Ω
Drain-source on-state resistance $V_{GS}=-4.5, I_D=-0.39\text{A}$	$R_{DS(on)}$	-	0.7	1.2	

Electrical Characteristics, at $T_j = 25\text{ }^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

Dynamic Characteristics

Transconductance	g_{fs}	$ V_{DS} \geq 2 * I_D * R_{DS(on)max}$ $I_D = -0.31\text{A}$	0.35	0.7	-	S
Input capacitance	C_{iss}	$V_{GS} = 0, V_{DS} = -15\text{V},$ $f = 1\text{MHz}$	-	45	56	pF
Output capacitance	C_{oss}		-	21	26	
Reverse transfer capacitance	C_{rss}		-	17	22	
Turn-on delay time	$t_{d(on)}$	$V_{DD} = -10\text{V}, V_{GS} = -4.5\text{V},$ $I_D = -0.39\text{A}, R_G = 6\Omega$	-	3.8	5.7	ns
Rise time	t_r		-	5	7.5	
Turn-off delay time	$t_{d(off)}$		-	5.1	7.6	
Fall time	t_f		-	3.2	4.8	

Gate Charge Characteristics

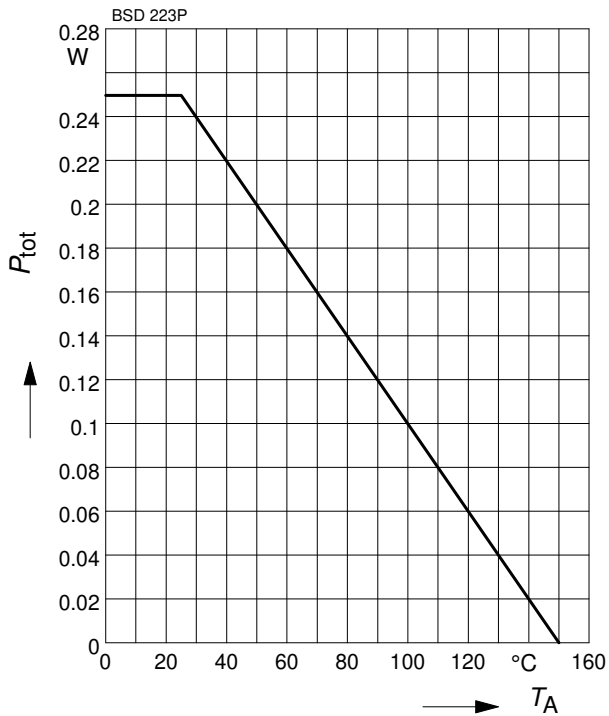
Gate to source charge	Q_{gs}	$V_{DD} = -10\text{V}, I_D = -0.39\text{A}$	-	-0.04	-0.05	nC
Gate to drain charge	Q_{gd}		-	-0.4	-0.5	
Gate charge total	Q_g	$V_{DD} = -10\text{V}, I_D = -0.39\text{A},$ $V_{GS} = 0 \text{ to } -4.5\text{V}$	-	-0.5	-0.62	
Gate plateau voltage	$V_{(plateau)}$	$V_{DD} = -10\text{V}, I_D = -0.39\text{A}$	-	-2.2	-2.7	V

Reverse Diode

Inverse diode continuous forward current	I_S	$T_A = 25\text{ }^\circ\text{C}$	-	-	-0.39	A
Inv. diode direct current, pulsed	I_{SM}		-	-	-1.56	
Inverse diode forward voltage	V_{SD}	$V_{GS} = 0, I_F = -0.39$	-	-1	-1.33	V
Reverse recovery time	t_{rr}	$V_R = -10\text{V}, I_F = I_D ,$ $di_F/dt = 100\text{A}/\mu\text{s}$	-	7.6	9.5	ns
Reverse recovery charge	Q_{rr}		-	1.1	1.4	

1 Power dissipation

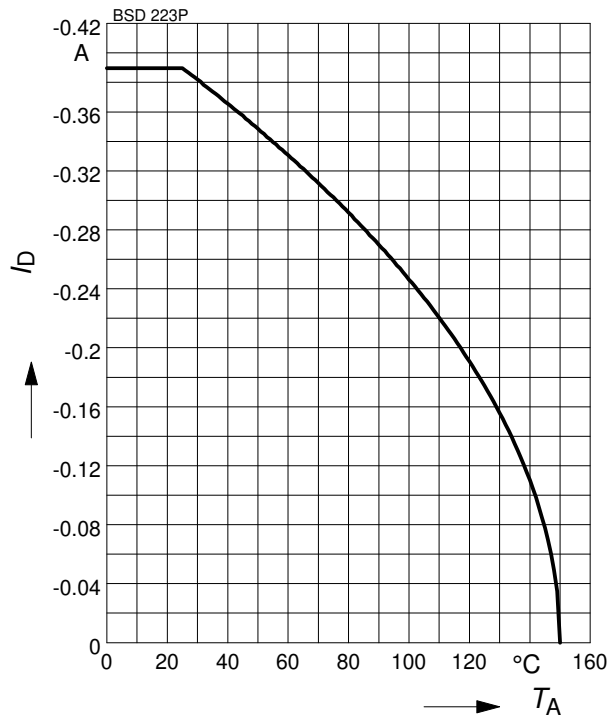
$P_{tot} = f(T_A)$



2 Drain current

$I_D = f(T_A)$

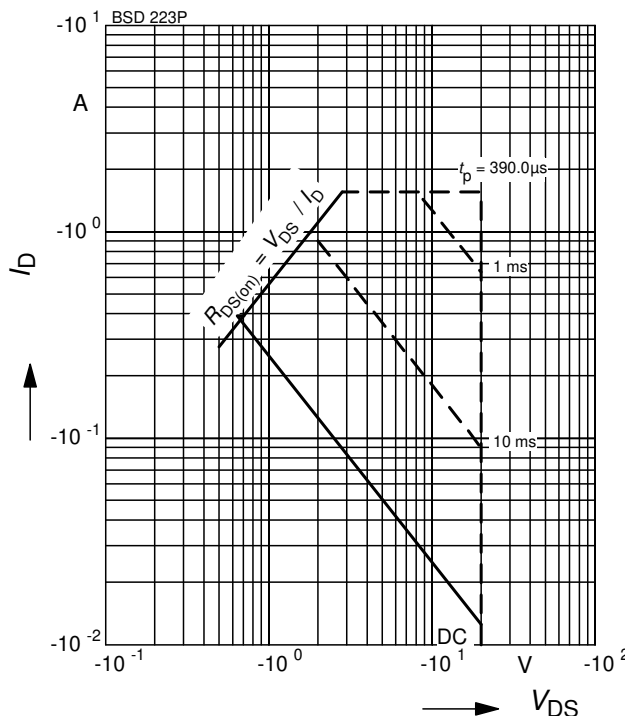
parameter: $|V_{GS}| \geq 4.5 \text{ V}$



3 Safe operating area

$I_D = f(V_{DS})$

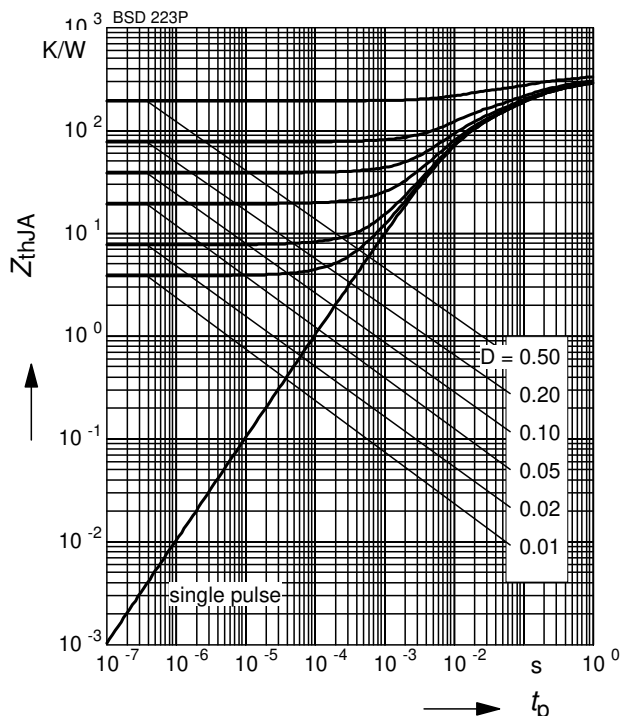
parameter: $D = 0, T_A = 25 \text{ °C}$



4 Transient thermal impedance

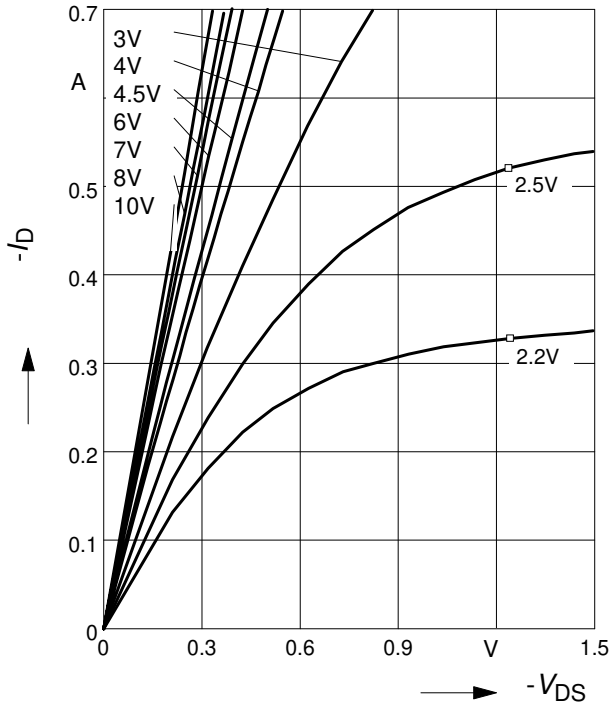
$Z_{thJA} = f(t_p)$

parameter: $D = t_p/T$



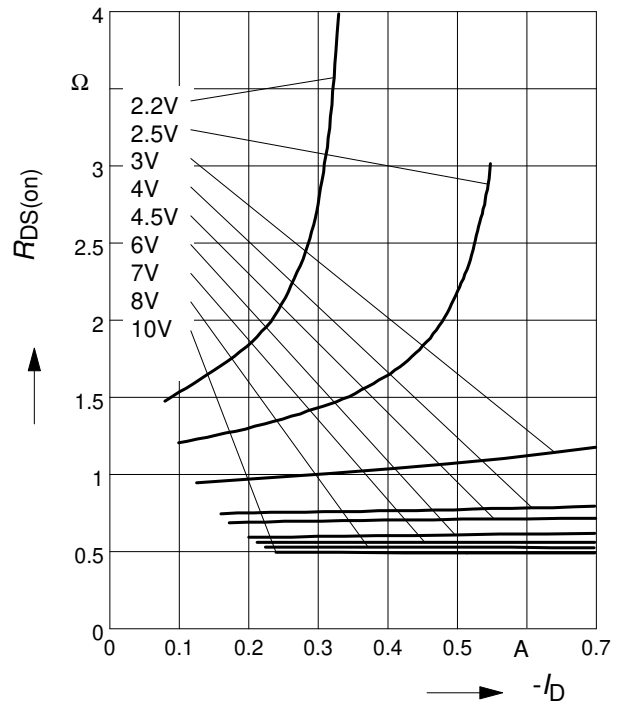
5 Typ. output characteristic

$I_D = f(V_{DS})$
parameter: $T_j = 25^\circ\text{C}$



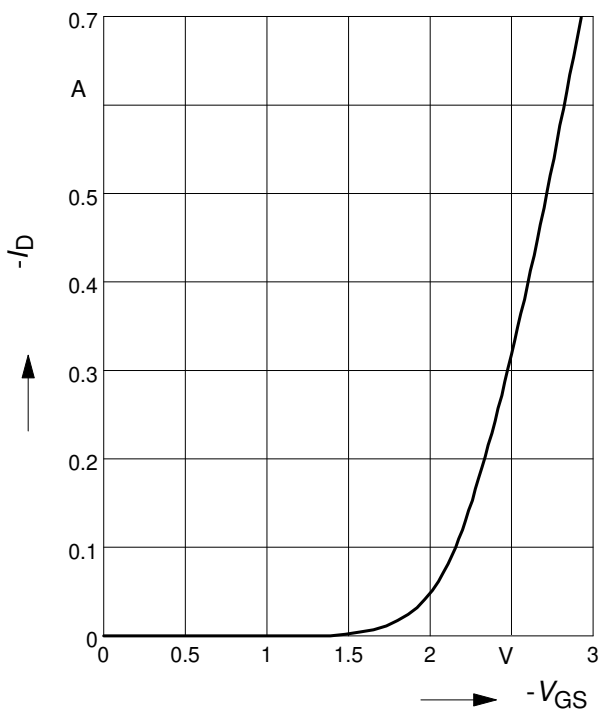
6 Typ. drain-source on resistance

$R_{DS(on)} = f(I_D)$
parameter: V_{GS}



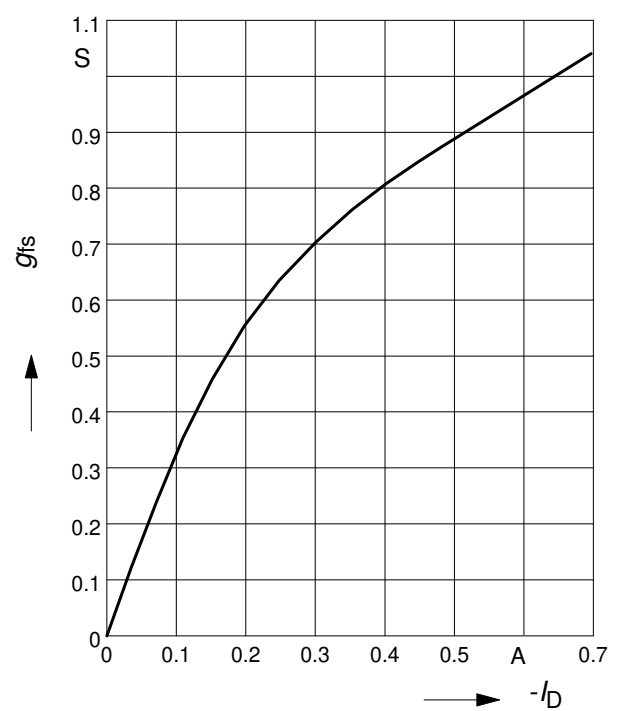
7 Typ. transfer characteristics

$I_D = f(V_{GS})$; $|V_{DS}| \geq 2 \times |I_D| \times R_{DS(on)max}$
parameter: $T_j = 25^\circ\text{C}$



8 Typ. forward transconductance

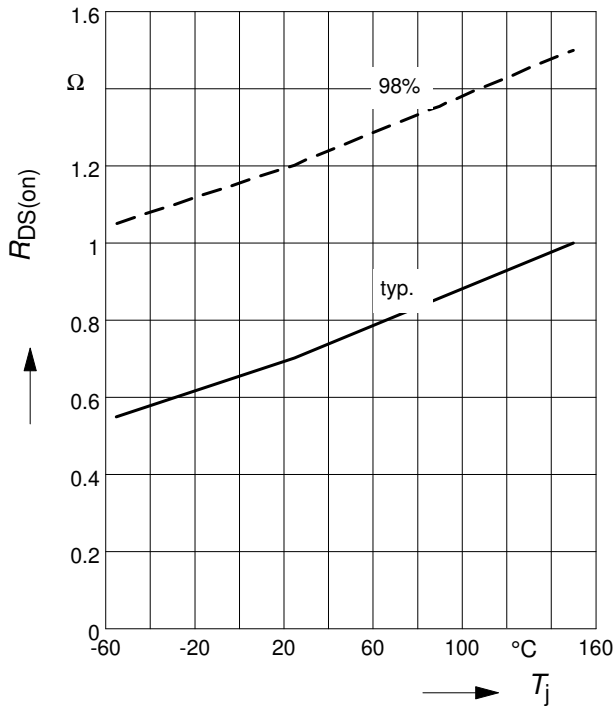
$g_{fs} = f(I_D)$
parameter: $T_j = 25^\circ\text{C}$



9 Drain-source on-resistance

$$R_{DS(on)} = f(T_j)$$

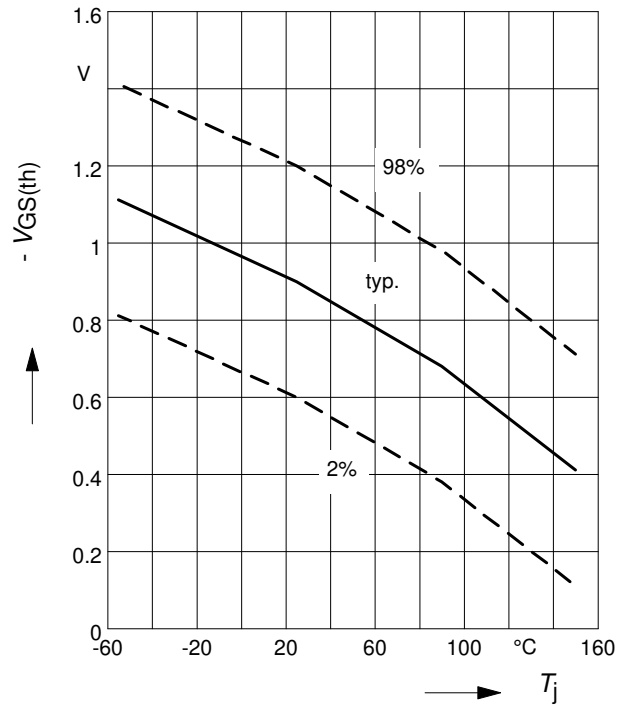
parameter: $I_D = -0.39$ A, $V_{GS} = -4.5$ V



10 Typ. gate threshold voltage

$$V_{GS(th)} = f(T_j)$$

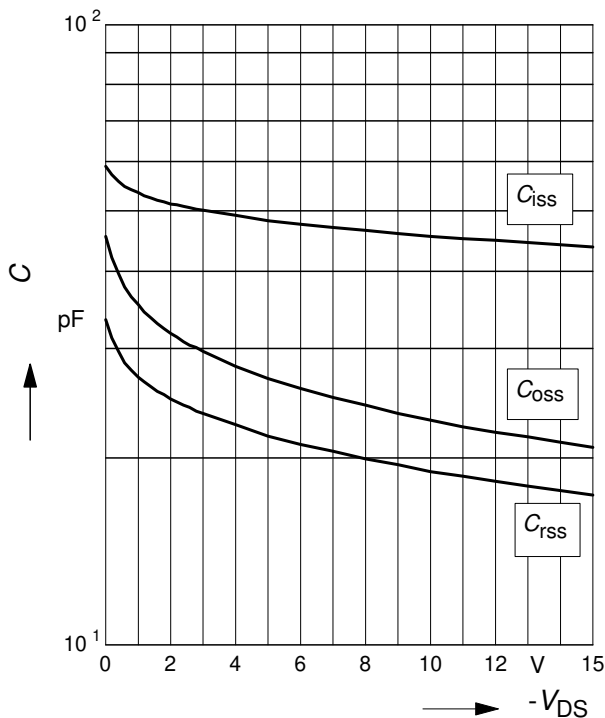
parameter: $V_{GS} = V_{DS}$



11 Typ. capacitances

$$C = f(V_{DS})$$

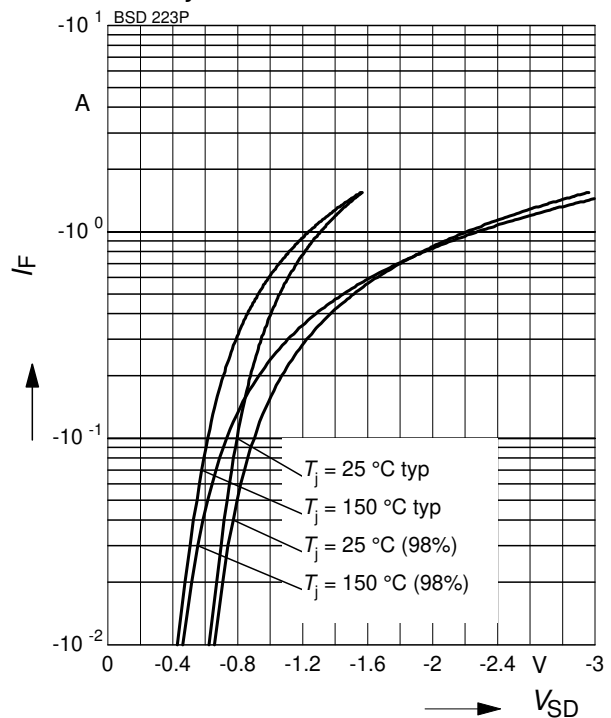
parameter: $V_{GS}=0$, $f=1$ MHz



12 Forward character. of reverse diode

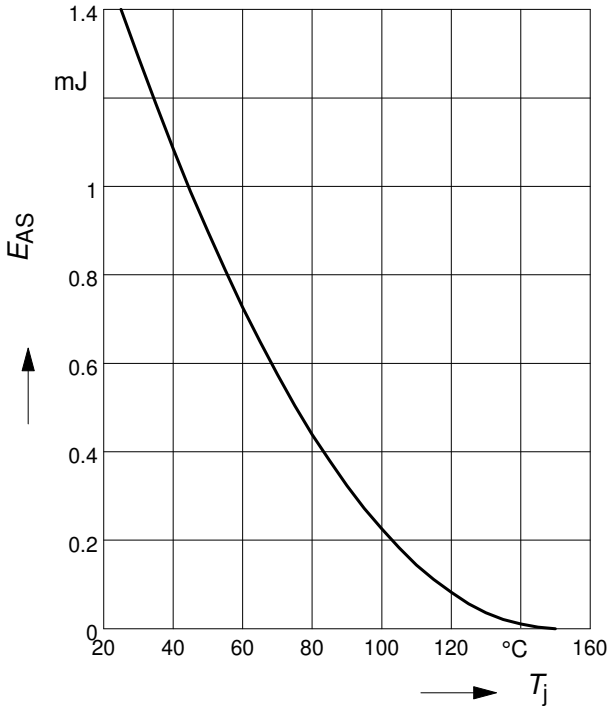
$$I_F = f(V_{SD})$$

parameter: T_j



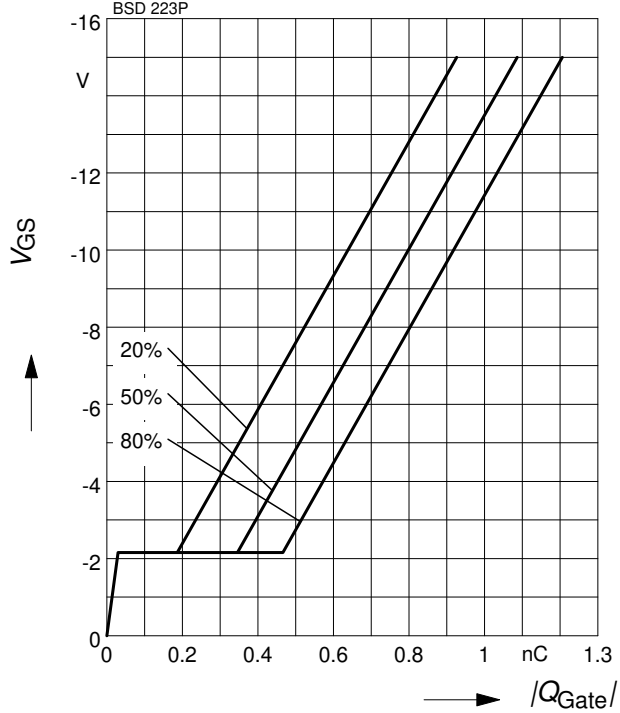
13 Typ. avalanche energy

$E_{AS} = f(T_j)$, par.: $I_D = -0.39$ A
 $V_{DD} = -10$ V, $R_{GS} = 25 \Omega$



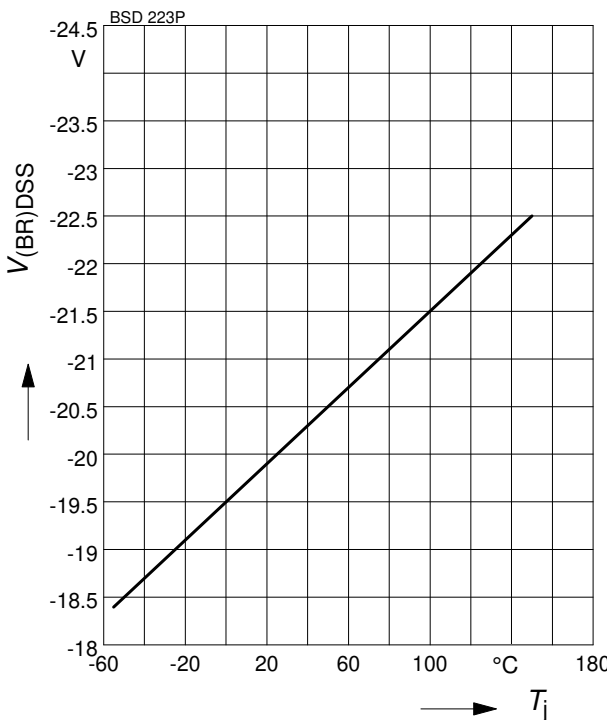
14 Typ. gate charge

$V_{GS} = f(Q_{Gate})$
 parameter: $I_D = -0.39$ A pulsed; $T_j = 25$ °C

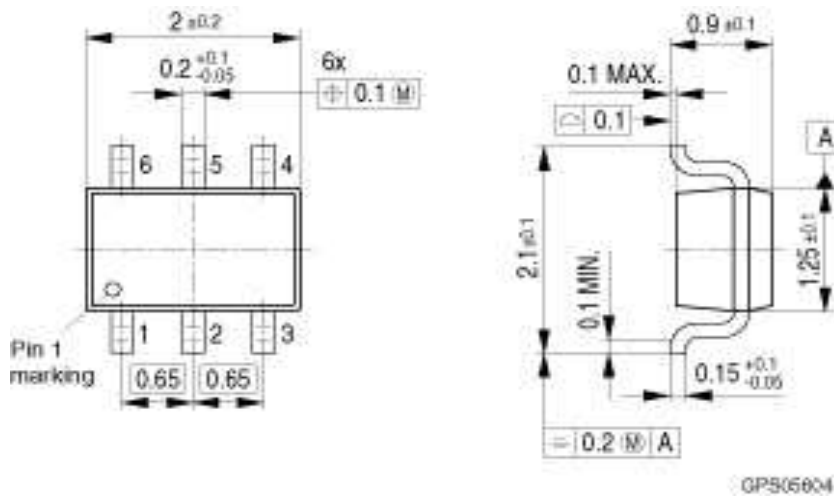


15 Drain-source breakdown voltage

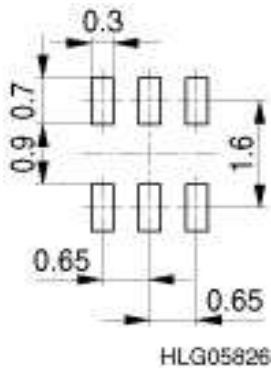
$V_{(BR)DSS} = f(T_j)$



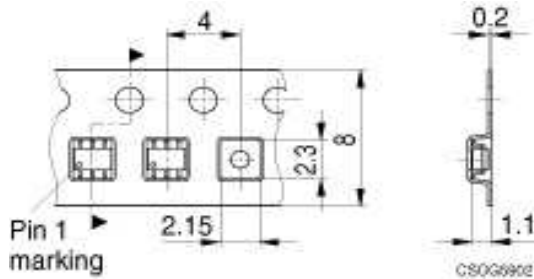
Package Outline:



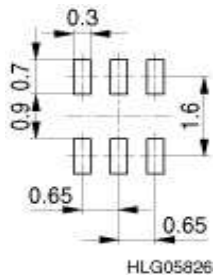
Footprint:



Packaging:



Reflow soldering:



Dimensions in mm

For symmetric types there is no defined Pin 1 orientation in the reel.

Published by
Infineon Technologies AG
81726 Munich, Germany
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